

# **30V N-Channel Trench MOSFET**

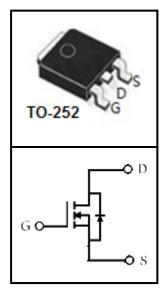
#### **FEATURES**

- Super Low Gate Charge
- 100% EAS Guaranteed
- RoHS compliant
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

#### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Hard switched and high frequency circuits





Device Marking and Package Information				
Device	Package	Marking		
CTD03N003	TO-252	CTD03N003		

<b>Absolute Maximum Ratings</b> at T <sub>j</sub> = 25°C unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V <sub>GS</sub> = 0V)		V <sub>DSS</sub>	30	V
Continuous Drain Current T <sub>C</sub> = 25°C	(note1)		180	А
Continuous Drain Current T <sub>C</sub> = 100°C	(note1)	I <sub>D</sub>	120	A
Pulsed Drain Current	(note2)	I <sub>DM</sub>	380	А
Gate Source Voltage		V <sub>GSS</sub>	±20	V
Single Pulse Avalanche Energy	(note3)	E <sub>AS</sub>	267	mJ
Power Dissipation $T_C = 25^{\circ}C$	(note4)	P <sub>D</sub>	90	W
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	-55~+175	°C

Thermal Characteristics					
Parameter	Symbol	Value	Unit		
Thermal Resistance, Junction-Case (note1)	$R_{\theta JC}$	1.4	°C/W		
Thermal Resistance, Junction-Ambient (t≤10S) (note1)	$R_{\theta JA}$	25	°C/W		
Thermal Resistance Junction-ambient (Steady State)	$R_{\theta JA}$	62	°C/W		



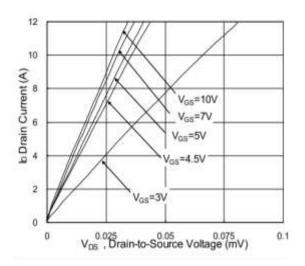
Electrical Characteristics T <sub>j</sub> = 25°C unless otherwise specified						
Desembles	0	T O . IIII	Value			
Parameter	Symbol	Test Conditions		Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	uA
2010 Gato Voltago Brain Garront	פטי	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 55^{\circ}C$			5	uA
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20V$			±100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	1.5	2.5	V
Drain-Source On-Resistance (note2)	R <sub>DS(on)</sub>	$V_{GS} = 10V, I_D = 30A$		2.3	3	mΩ
Brain Godice On Resistance (notez)	**DS(on)	$V_{GS} = 4.5V, I_{D} = 15A$		3.0	4	mΩ
Dynamic						
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0V$ ,		5935		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15V$ ,		725		
Reverse Transfer Capacitance	$C_{rss}$	f = 1.0MHz		538		
Total Gate Charge (4.5V)	$Q_g$			56.9		пС
Gate-Source Charge	$Q_gs$	$V_{DS} = 15V, I_{D} = 15A,$ $V_{GS} = 4.5V$		13.8		
Gate-Drain Charge	$Q_gd$			23.5		
Turn-on Delay Time	$t_{d(on)}$			20.1		
Turn-on Rise Time	t <sub>r</sub>	$V_{DS} = 15V,$ $V_{GS} = 10V, R_{G} = 3.3\Omega$		6.3		ns
Turn-off Delay Time	$t_{d(off)}$	$I_D = 15A$		124.6		
Turn-off Fall Time	t <sub>f</sub>			15.8		
<b>Body Diode Characteristics</b>						
Continuous Body Diode Current	Is	T 05.00			180	А
Pulsed Diode Forward Current	I <sub>SM</sub>	T <sub>C</sub> = 25 °C			380	
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}\text{C}, I_{SD} = 5\text{A}, V_{GS} = 0\text{V}$			1.2	V
Reverse Recovery Time	t <sub>rr</sub>	TJ=25°C I <sub>F</sub> =30A,		25		nS
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt=100A/μs		12		nc

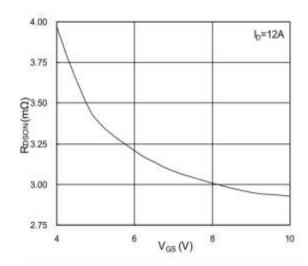
#### **Notes**

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\leq\!300 us$  , duty cycle  $\!\leq\!2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD =25V,VGS =10V,L=0.1mH  $\,$
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



## **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted





**Fig.1 Typical Output Characteristics** 

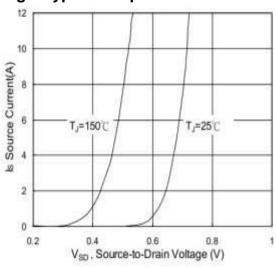


Fig.2 On-Resistance vs. G-S Voltage

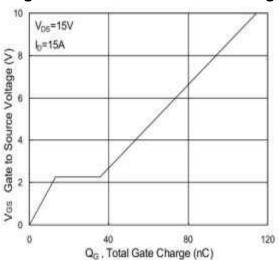


Fig.3 Forward Characteristics of Reverse Diode

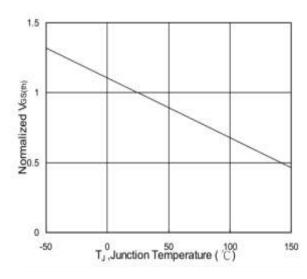


Fig.5 Normalized VGS(th) vs. TJ

Fig.4 Gate-Charge Characteristics

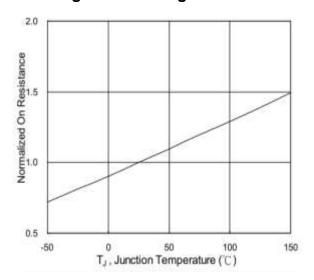


Fig.6 Normalized RDSON vs. TJ



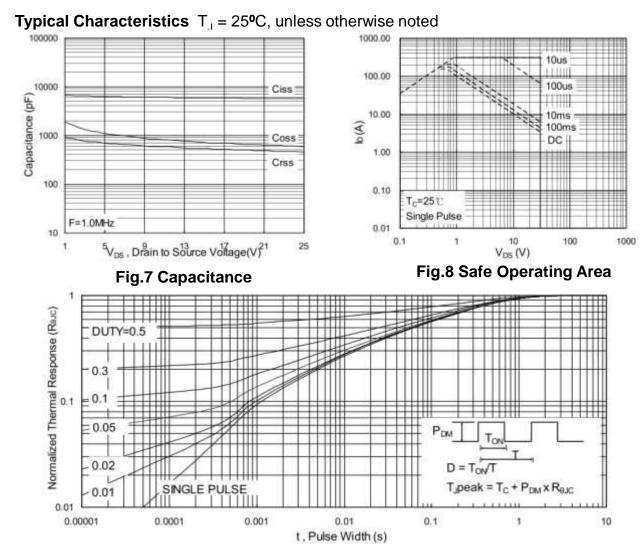


Fig.9 Normalized Maximum Transient Thermal Impedance



Figure A: Gate Charge Test Circuit and Waveform

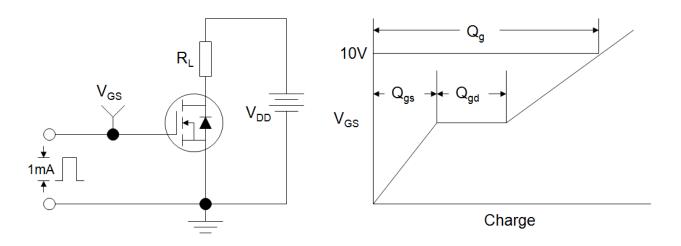


Figure B: Resistive Switching Test Circuit and Waveform

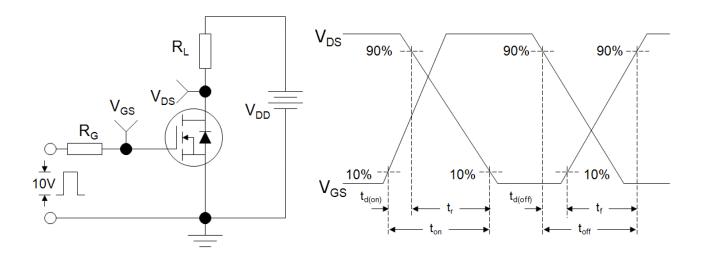
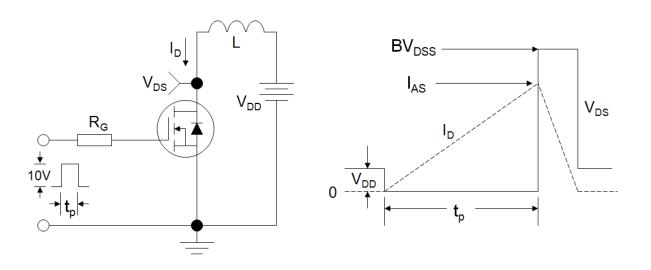
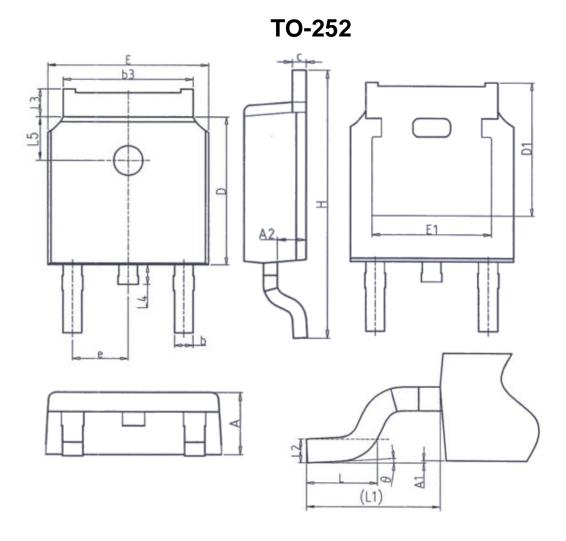


Figure C: Unclamped Inductive Switching Test Circuit and Waveform







Unit: mm			
Symbol	Min.	Max.	
Α	2. 20	2. 40	
A1	0.00	0. 20	
A2	0. 97	1. 17	
b	0. 68	0. 90	
b3	5. 20	5. 50	
С	0. 43	0. 63	
D	5. 98	6. 22	
D1	D1 5. 30REF		
E	6. 40	6. 80	
E1	4. 63	-	

Unit: mm				
Symbol	Min. Max.			
е	2. 286BSC			
Н	9. 40	10.50		
L	1. 38	1. 75		
L1	2. 90REF			
L2	0. 51BSC			
L3	0.88	1. 28		
L4	_	1.00		
L5	1. 65	1. 95		
θ	0°	8°		



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